



Optical Measurements in Industrial Inspection BMTA Seminar at mmc2017

Thursday 6 July

09:30 Tea and Coffee

09:45 Introduction
Michelle Peckham, RMS President

10:00 Aspirin to Aircraft - Measurement and Testing
Mike Ashton, Intertek

10:30 Transmission Electron Microscopy as a Quality Control Tool to Accurately Measure Layer Thicknesses
Thomas Walther, University of Sheffield

11:00 New Industrial Applications for Scanning Electron Microscopy
Laxman Kasireddy, Ayerst Environmental

11:30 Lunch and Exhibition
A lunch voucher will be included with registration

13:30 BAE Systems Presentation
Jamie Lindsay, BAE Systems Submarines

14:00 Laser-based Applications
Leon Lobo, BINDT

14:30 Closing Discussion

15:00 Seminar Close and mmc2017 Closing Drinks Reception

